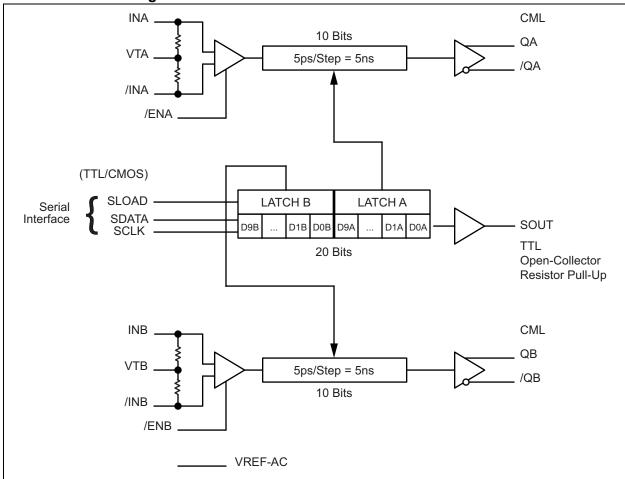
Functional Block Diagram



1.0 ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings †

Supply Voltage (V_{CC}) Input Voltage (V_{IN}) CML Output Voltage (V_{OUT}) Current (Source or Sink Current on V_{T}) Input Current (Source or Sink Current on IN, /IN) Current (V_{REF} , Source or Sink Current on V_{REF-AC}) (Note 1)	-0.5V to V _{CC} V _{CC} – 1.0V to V _{CC} + 0.5V±70 mA±35 mA
Operating Ratings ‡ Supply Voltage (V _{CC} for T _A = -40°C to +85°C)	+2.375V to +2.625V
Supply Voltage (V_{CC} for $T_A = -40^{\circ}\text{C}$ to +75°C)	

[†] Notice: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or any other conditions above those indicated in the operational sections of this specification is not intended. Exposure to maximum rating conditions for extended periods may affect device reliability.

‡ Notice: The device is not guaranteed to function outside its operating ratings.

Note 1: Due to the limited drive capability, use for input of the same package only.

TABLE 1-1: DC ELECTRICAL CHARACTERISTICS

Electrical Characteristics: $T_A = -40$ °C to +85 °C, Channels A and B, unless noted. Note 1

Parameter	Symbol	Min.	Тур.	Max.	Units	Conditions
		2.375	2.5	2.625		$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$
Power Supply Voltage Range	V _{CC}	3.0	3.3	3.6	V	$T_A = -40^{\circ}C \text{ to } +75^{\circ}C$
Tower Supply Voltage Name	VCC	3.0	3.3	3.6	٧	$T_A = -40$ °C to +85°C, Airflow = 500 lfpm
Power Supply Current	I _{cc}		195	250	mA	Maximum V _{CC} , Both Channels Combined, Output Load Included
Input Resistance (IN-to-VT, /IN-to-VT)	R _{IN}	45	50	55	Ω	_
Differential Input Resistance (IN-to-/IN)	R _{DIFF_IN}	90	100	110	Ω	_
Input HIGH Voltage (IN, /IN)	V_{IH}	1.2		V_{CC}	V	_
Input LOW Voltage (IN, /IN)	V _{IL}	0		V _{IH} – 0.1	>	_
Input Voltage Swing (IN, /IN)	V_{IN}	0.1	_	1.0	V	See Figure 5-1
Differential Input Voltage Swing (IN - /IN)	V _{DIFF_IN}	0.2		_	٧	See Figure 5-2
Output Reference Voltage	V _{REF-AC}	V _{CC} – 1.3	V _{CC} – 1.2	V _{CC} – 1.1	V	_
Voltage from Input to V _T	$V_{T_{_IN}}$		_	1.28	V	_

Note 1: The circuit is designed to meet the DC specifications show in the table above after thermal equilibrium has been established.

TABLE 1-2: CML OUTPUTS DC ELECTRICAL CHARACTERISTICS

Electrical Characteristics: V_{CC} = +2.5V +5% or +3.3V ±10%, R_L = 100 Ω across the outputs; T_A = -40°C to +85°C, unless otherwise stated. Note 1

Parameter	Symbol	Min.	Тур.	Max.	Units	Conditions
Output HIGH Voltage	V _{OH}	V _{CC} – 0.02	V _{CC} – 0.01	V _{CC}	V	$R_L = 50\Omega$ to V_{CC}
Output Voltage Swing	V _{OUT}	325	400		mV	See Figure 5-1
Differential Output Voltage Swing	V _{DIFF_OUT}	650	800		mV	See Figure 5-2
Output Source Impedance	R _{OUT}	45	50	55	Ω	_

Note 1: The circuit is designed to meet the DC specifications shown in the above table after thermal equilibrium has been established.

TABLE 1-3: LVTTL/CMOS DC ELECTRICAL CHARACTERISTICS

Electrical Characteristics: V_{CC} = 2.5V ±5% or 3.3V ±10%; T_A = -40°C to +85°C; unless otherwise stated. Note 1

Parameter	Symbol	Min.	Тур.	Max.	Units	Conditions
Input High Voltage	V _{IH}	2.0	_	_	V	_
Input Low Voltage	V_{IL}	_	_	0.8	V	_
Input High Current	I _{IH}	_	_	150	μA	V _{IH} = V _{CC}
Input Low Current	I _{IL}	_	_	50	μA	V _{IL} = 0.8V
Output LOW Voltage	\/	_	_	0.55	V	SOUT Pin; I _{OL} = 1 mA
Output High Leakage Current	V _{OL}	_	_	100	μA	SOUT = V _{CC}

Note 1: The circuit is designed to meet the DC specifications shown in the above table after thermal equilibrium has been established.

TABLE 1-4: AC ELECTRICAL CHARACTERISTICS

Electrical Characteristics: $T_A = -40$ °C to +85°C, Channels A and B, unless otherwise stated. Note 1

Parameter	Symbol	Min.	Тур.	Max.	Units	Conditions
Maximum Operating	f	1.6	_	_	GHz	Clock: V _{OUT} Swing >200 mV _{pk}
Frequency	f _{MAX}	3.2	_	_	Gbps	NRZ Data
		1000	_	2000		IN to Q; D[0-9] = 0
		5500	_	7500		IN to Q; D[0-9] = 1023
Propagation Delay	t _{pd}	1000	_	2500	ps	/EN to Q: D[0-9] = 0; $V_{TH} = V_{CC}/2$
		2000		4500		SDATA to SOUT (D0-D9 = Low), No load
Programmable Range	t _{RANGE}	4150	5115		ps	$t_{pd(MAX)} - t_{pd(MIN)}$
			5			D0 High
			10			D1 High
			20			D2 High
	Δt	_	40	_		D3 High
		_	80	_		D4 High
Step Delay		_	160	_	ps	D5 High
Step Delay		_	320	_	ρs	D6 High
			640			D7 High
			1280			D8 High
		_	2560	_		D9 High
		_	5115	_		D0-D9 High
		– 5	_	25		Monotonic
Integral Non-Linearity	INL	–15	_	15	ps	Note 2
		400				SDATA to SCLK
Set-Up Time	t _S	400	_	_	ps	SCLK to SLOAD, Note 3
		300	_	_		/EN to IN, Note 4
		300	_	_		SLOAD to SCLK, Note 5
Hold Time	t _H	-100	_	_	ps	IN to /EN, Note 6
		200	_	_		SCLK to SDATA

SY89297U

TABLE 1-4: AC ELECTRICAL CHARACTERISTICS (CONTINUED)

Electrical Characteristics: $T_A = -40^{\circ}$ C to +85°C, Channels A and B, unless otherwise stated. Note 1

Parameter	Symbol	Min.	Тур.	Max.	Units	Conditions
Pulse Width	t _{PW}	1000	_	_	ps	SLOAD
Release Time	t _R	800	_	_	ps	/EN to IN, Note 7
Cycle-to-Cycle Jitter		_	_	2	ps _{RMS}	Note 8
Total Jitter	t _{JITTER}	_	_	20	ps _{PP}	Note 9
Random Jitter		_	_	2	ps _{RMS}	Note 10
Output Rise/Fall Time	t _r /t _f	30	55	80	ps	20% to 80% (Q)
Duty Cycle	_	45	_	55	%	Input frequency = 1.6 GHz

- Note 1: High frequency AC electricals are guaranteed by design and characterization.
 - 2: INL (Integral Non-Linearity) is defined from its corresponding point on the ideal delay versus D[9:0] curve as the deviation from its ideal delay. The maximum difference is the INL. Theoretical Ideal Linearity (TIL) = (measured maximum delay measured minimum delay) ÷ 1023. INL = measured delay (measured minimum delay + (step number x TIL)).
 - **3:** SCLK has to transition L-H a setup time before the SLOAD H-L transition to ensure the valid data is properly latched. See Figure 4-2.
 - 4: This setup time is the minimum time that /EN must be asserted prior to the next transition of IN / /IN to prevent an output response greater than ±75 mV to that IN or /IN transition. See Figure 4-3.
 - 5: SCLK has to transition L-H a hold time after the SLOAD H-L transition to ensure that the valid data is properly latched before starting to load new data. See Figure 4-2.
 - **6:** This hold time is the minimum time that /EN must remain asserted after a negative going transition of IN to prevent an output response greater than ±75 mV to the IN transition. See Figure 4-3.
 - 7: This release time is the minimum time that /EN must be de-asserted prior to the next IN / /IN transition to affect the propagation delay of IN to Q less than 1 ps. See Figure 4-3.
 - 8: Cycle-to-cycle jitter definition: The variation of periods between adjacent cycles over a random sample of adjacent cycle pairs $T_{iitter\ cc} = T_n T_n + 1$, where T is the time between rising edges of the output signal.
 - **9:** Total jitter definition: With an ideal clock input, no more than one output edge in 10¹² output edges will deviate by more than the specified peak-to-peak jitter value.
 - **10:** Random jitter definition: Jitter that is characterized by a Gaussian distribution, unbounded and is quantified by its standard deviation and mean. Random jitter is measured with a K28.7 comma detect pattern, measured at 1.5 Gbps.

TEMPERATURE SPECIFICATIONS (Note 1)

Parameters	Sym.	Min.	Тур.	Max.	Units	Conditions			
Temperature Ranges									
Junction Operating Temperature	T_J	_	_	+125	°C	_			
Storage Temperature Range	T _S	-65	_	+150	°C	_			
Lead Temperature	_	_	_	+260	°C	Soldering, 20s			
Ambient Temperature Range	T _A	-40	_	+85	°C	_			
Package Thermal Resistances, Note 2									
Thormal Desigtance OFN 24	θ_{JA}	_	43	_	°C/W	Still-Air			
Thermal Resistance QFN-24	Ψ_{JB}	_	30.5	_	°C/W	Junction-to-Board			

- Note 1: The maximum allowable power dissipation is a function of ambient temperature, the maximum allowable junction temperature and the thermal resistance from junction to air (i.e., T_A , T_J , θ_{JA}). Exceeding the maximum allowable power dissipation will cause the device operating junction temperature to exceed the maximum +125°C rating. Sustained junction temperatures above +125°C can impact the device reliability.
 - **2:** Thermal performance on QFN packages assumes exposed pad is soldered (or equivalent) to the device most negative potential (GND).

2.0 TYPICAL PERFORMANCE CURVES

Note: The graphs and tables provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

 V_{CC} = +2.5V, GND = 0V, V_{IN} = 100 mV, R_L = 100 Ω across the outputs, T_A = +25°C for Figure 2-1.

 V_{CC} = 2.5V or 3.3V, GND = 0V, V_{IN} = 100 mV, R_L = 100 Ω across the outputs, T_A = +25°C, Maximum Delay (D0-D9 = High) for Figure 2-2 through Figure 2-5.

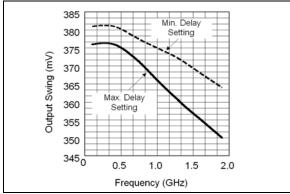


FIGURE 2-1: Output Swing vs. Frequency.

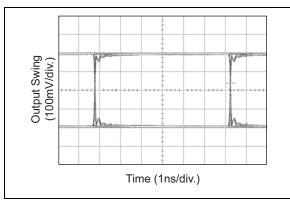


FIGURE 2-2: 155 Mbps Clock.

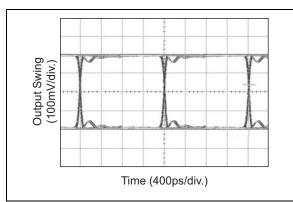


FIGURE 2-3: 622 Mbps Clock.

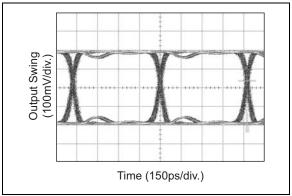


FIGURE 2-4: 1.6 Gbps Clock.

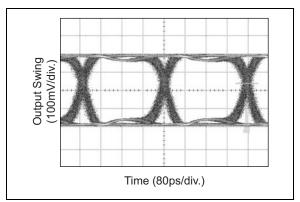


FIGURE 2-5: 3.2 Gbps Clock.

2.1 Phase Noise Chart

 V_{CC} = +2.5V, GND = 0V, V_{IN} = 100 mV, R_L = 100 Ω across the outputs, T_A = +25°C.

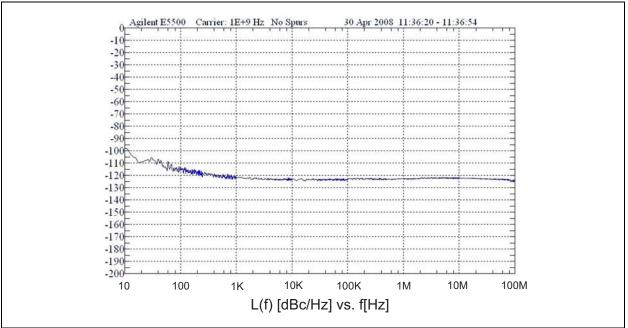


FIGURE 2-6: f_C: 1 GHz. Delay Setting: 00001 00110 (2 ns).

3.0 PIN DESCRIPTIONS

The descriptions of the pins are listed in Table 3-1.

TABLE 3-1: PIN FUNCTION TABLE

IABLE 3-1:	PIN FUNCTION	
Pin Number	Pin Name	Description
1, 2	INA, /INA	Channel A Differential Input: INA and /INA pins receive the Channel A data. QA and /QA are the delayed product of INA and /INA. Each input is internally terminated to VTA through a 50Ω resistor (100Ω across INA and /INA).
3	VTA	Input A Termination Center-Tap: Each side of the differential input pair terminates to this pin. This pin provides a center-tap to a termination network for maximum interface flexibility. See the Input Interface Applications section.
4	VTB	Input B Termination Center-Tap: Each side of the differential input pair terminates to this pin. This pin provides a center-tap to a termination network for maximum interface flexibility. See the Input Interface Applications section.
5, 6	INB, /INB	Channel B Differential Input: INB and /INB pins receive the Channel B data. QB and /QB are the delayed product of INB and /INB. Each input is internally terminated to VTB through a 50Ω resistor (100Ω across INB and /INB).
7	VREF-AC	Reference Voltage Output: For AC-coupled input signals, this pin can bias the inputs IN and /IN. Connect VREF-AC directly to the VT input pin for each channel. De-couple to V_{CC} using a 0.01 μ F capacitor. Maximum sink/source current is ±0.5 mA. For DC-coupled input applications, leave VREF-AC pin floating.
8, 11, 20	GND, Exposed Pad	Negative Supply: Exposed pad must be connected to a ground plane that is the same potential as the ground pins.
9	/ENA	CMOS/TTL-Compatible Enable Input: When the /ENA pin is pulled HIGH, QA is held LOW and /QA goes HIGH after the programmed delay propagates through the part. /ENA contains a 67 k Ω pull-down resistor and defaults LOW when left floating. Logic threshold level is $V_{CC}/2$
10	/ENB	CMOS/TTL-Compatible Enable Input: When the /ENB pin is pulled HIGH, QB is held LOW and /QB goes HIGH after the programmed delay propagates through the part. /ENB contains a 67 k Ω pull-down resistor and defaults LOW when left floating. Logic threshold level is $V_{CC}/2$
12, 15, 16, 19	VCC	Power Supply: Bypass each supply pin with 0.1 μ F//0.01 μ F low-ESR capacitors. See Table 1-1 for more details. 2.5V ±5% or 3.3V ±10%.
13, 14	/QB, QB	CML Differential Output: QB and /QB are the delayed product of INB, /INB. CML outputs are terminated at the destination with 100 Ω across the pair. See the CML Output Termination section.
17, 18	/QA, QA	CML Differential Output: QA and /QA are the delayed product of INA, /INA. CML outputs are terminated at the destination with 100Ω across the pair. See the CML Output Termination section.
21	SOUT	CMOS/TTL-compatible output: This pin is used to support cascading multiple SY89297U delay lines. Serial data is clocked into the SDATA input and is clocked out of SOUT into the next SY89297U delay line. SOUT pin includes an internal 550Ω pull-up resistor.
22, 23	SDATA, SCLK	CMOS/TTL-compatible 3-pin serial programming control inputs: The 3-pin serial control sets each channel's IN to Q delay. DA(0:9) control channel A delay. DB(0:9) control channel B. To program the two channels, insert a 20-bit word (DA0:DA9 and DB0:DB9) into SDATA and clock in the control bits with SCLK. Maximum input frequency to SCLK is 40 MHz. Data is loaded into the serial registers on the L-H transition of SCLK. After all 20-bits are clocked in, SLOAD latches the new delay bits. These pins have internal pull-downs at the inputs. See Table 1-4 for delay values. Logic threshold level is $V_{\rm CC}/2$. SCLK and SDATA contain a 67 $k\Omega$ pull-down resistor and default LOW when left floating.

TABLE 3-1: PIN FUNCTION TABLE (CONTINUED)

Pin Number	Pin Name	Description
24	SLOAD	CMOS/TTL-compatible 3-pin serial programming control input: SLOAD controls the latches that transfer scanned data to the delay line. These latches are transparent when SLOAD is high. Data transfers from the latch to the delay line on a L-H transition of SLOAD. SLOAD has to transition H-L before new data is loaded in the scan chain. When SLOAD is high, the latches are transparent and SCLK cannot switch. Otherwise, new data will immediately transfer to the scan chain. Logic threshold level is $V_{\rm CC}/2$. SLOAD contains a 67 k Ω pull-down resistor and defaults LOW when left floating.

3.1 Truth Tables

TABLE 3-2: INPUTS/OUTPUTS

Inp	uts	Outputs			
INA, INB	/INA, /INB	QA, QB	/QA, /QB		
0	1	0	1		
1	0	1	0		

TABLE 3-3: INPUT ENABLE (LATCHES OUTPUTS)

/ENA, /ENB	Q, /Q (A, B)
1	Q = Low, /Q = HIGH
0	IN, /IN Delayed (normal operation)

4.0 TIMING DIAGRAMS

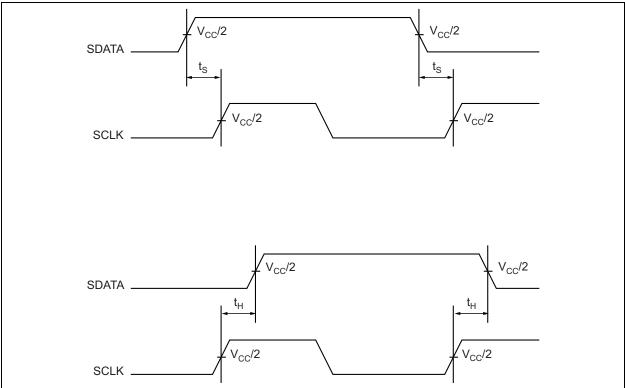


FIGURE 4-1: Setup and Hold Time: SDATA and SCLK.

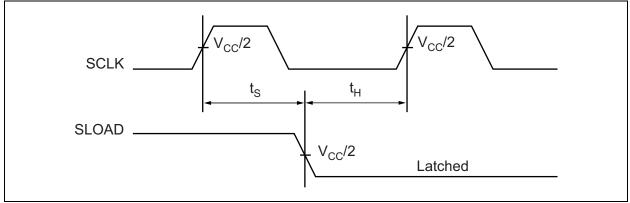


FIGURE 4-2: Setup and Hold Time: SCLK and SLOAD.

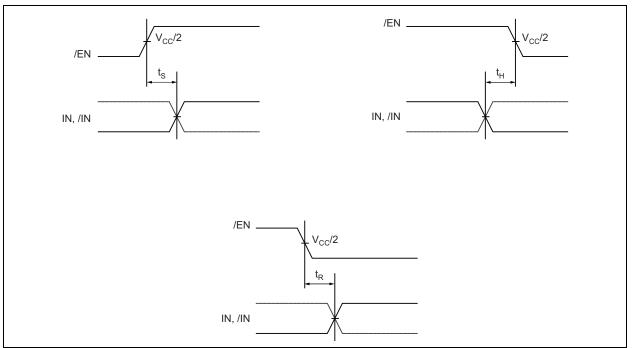


FIGURE 4-3: Setup, Hold, and Release Time: IN and /EN.

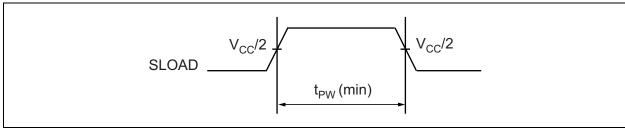


FIGURE 4-4: SLOAD Pulse Width (t_{PW}) .

5.0 VOLTAGE SWINGS

V_{IN}, V_{OUT} 400mV (typ.)

FIGURE 5-1: Single-Ended Voltage Swing.

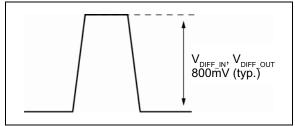


FIGURE 5-2: Differential Voltage Swing.

6.0 INPUT AND OUTPUT STAGES

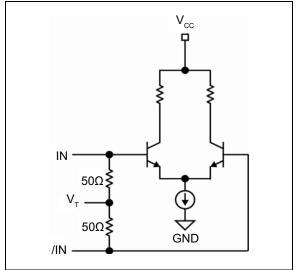


FIGURE 6-1: Input Stage.

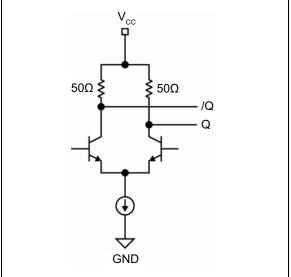


FIGURE 6-2: CML Output Stage.

7.0 INPUT INTERFACE APPLICATIONS

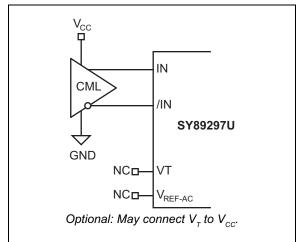


FIGURE 7-1: CML Interface (DC-Coupled).

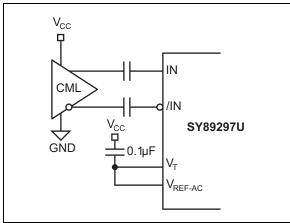


FIGURE 7-2: CML Interface (AC-Coupled).

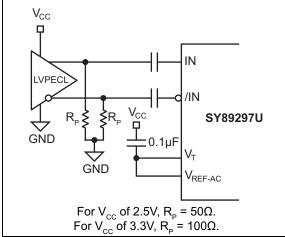


FIGURE 7-3: LVPECL Interface (AC-Coupled).

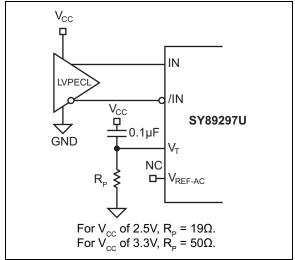


FIGURE 7-4: LVPECL Interface (DC-Coupled).

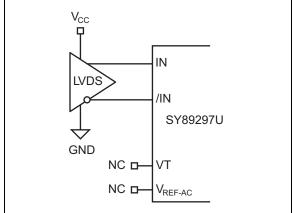


FIGURE 7-5: LVDS Interface (DC-Coupled).

8.0 CML OUTPUT TERMINATION

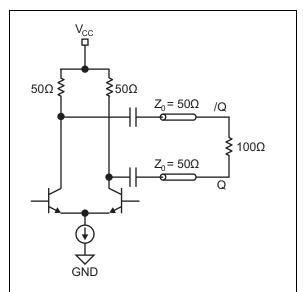
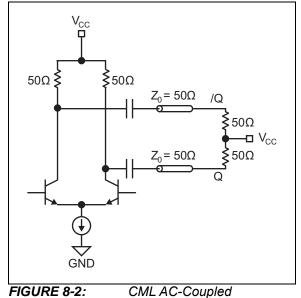


FIGURE 8-1: CML AC-Coupled Termination -100Ω Differential.



Termination – 50Ω to V_{CC} .

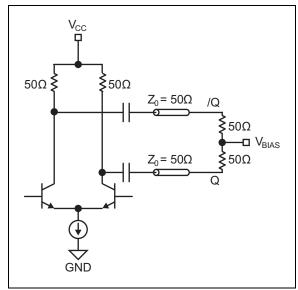


FIGURE 8-3: CML AC-Coupled Termination – 50Ω to V_{BIAS} .

9.0 PACKAGING INFORMATION

9.1 Package Marking Information

24-Lead QFN*



Example



Legend:XX...XProduct code or customer-specific informationYYear code (last digit of calendar year)YYYear code (last 2 digits of calendar year)

WW Week code (week of January 1 is week '01')

NNN Alphanumeric traceability code

COO Country of Origin

(e3) Pb-free JEDEC® designator for Matte Tin (Sn)

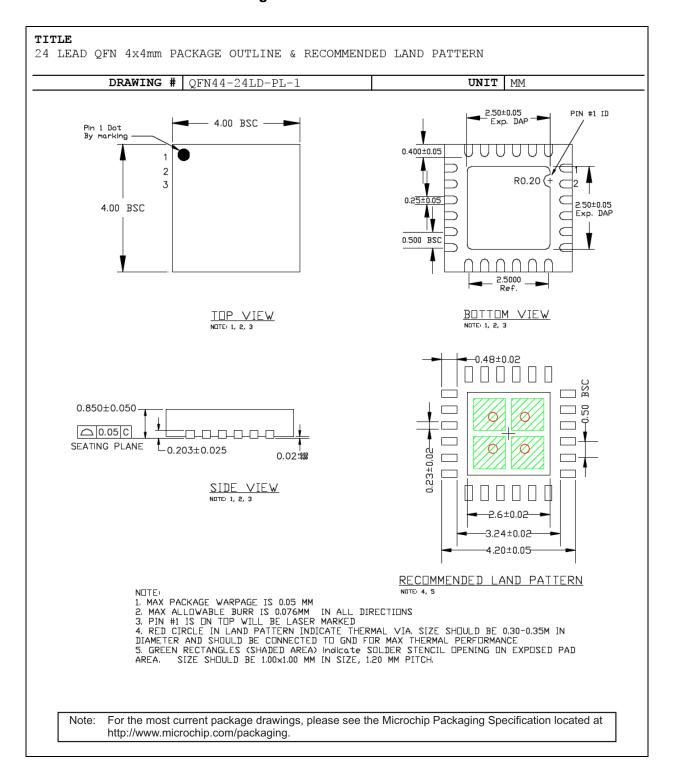
This package is Pb-free. The Pb-free JEDEC designator (e3) can be found on the outer packaging for this package.

•, ▲, ▼ Pin one index is identified by a dot, delta up, or delta down (triangle mark).

Note: In the event the full Microchip part number cannot be marked on one line, it will be carried over to the next line, thus limiting the number of available characters for customer-specific information. Package may or may not include the corporate logo.

Underbar (_) and/or Overbar (_) symbol may not be to scale.

24-Lead 4 mm x 4 mm QFN Package Outline and Recommended Land Pattern



APPENDIX A: REVISION HISTORY

Revision A (January 2018)

- Converted Micrel document SY89297U to Microchip data sheet DS20005835A.
- Minor text changes throughout.

SY89297U

NOTES:

PRODUCT IDENTIFICATION SYSTEM

To order or obtain information, e.g., on pricing or delivery, contact your local Microchip representative or sales office.

PART NO.	X	X	x	-XX	Examples:	
Device:	Voltage Option		Temperature Range	Special Processing	a) SY89297UMG:	2.5V/3.3V, 3.2 Gbps Precision CML Dual-Channel Programmable Delay, 2.5V/3.3V, 24-Lead 4 mm x 4 mm QFN, -40°C to +85°C (Pb-Free NiPdAu), 75/Tube
Voltage Option:	U =	2.5V/3.3V	·I Programmable [,	b) SY89297UMG-TF	2: 2.5V/3.3V, 3.2 Gbps Precision CML Dual-Channel Programmable Delay, 2.5V/3.3V, 24-Lead 4 mm x 4 mm QFN, -40°C to +85°C (Pb-Free NiPdAu), 1,000/Reel
Temperature Range: Special Processing:	G = H = <blank>= TR =</blank>		+85°C (Pb-Free N +75°C (Pb-Free N		c) SY89297UMH:	2.5V/3.3V, 3.2 Gbps Precision CML Dual-Channel Programmable Delay, 2.5V/3.3V, 24-Lead 4 mm x 4 mm QFN, -40°C to +75°C (Pb-Free NiPdAu), 75/Tube
					b) SY89297UMH-TR	2.5V/3.3V, 3.2 Gbps Precision CML Dual-Channel Programmable Delay, 2.5V/3.3V, 24-Lead 4 mm x 4 mm QFN, -40°C to +75°C (Pb-Free NiPdAu), 1,000/Reel
					catalog pa used for o the device Sales Offi	Reel identifier only appears in the int number description. This identifier is rdering purposes and is not printed on package. Check with your Microchip ce for package availability with the Reel option.

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NOTES:

Note the following details of the code protection feature on Microchip devices:

- Microchip products meet the specification contained in their particular Microchip Data Sheet.
- Microchip believes that its family of products is one of the most secure families of its kind on the market today, when used in the intended manner and under normal conditions.
- There are dishonest and possibly illegal methods used to breach the code protection feature. All of these methods, to our knowledge, require using the Microchip products in a manner outside the operating specifications contained in Microchip's Data Sheets. Most likely, the person doing so is engaged in theft of intellectual property.
- Microchip is willing to work with the customer who is concerned about the integrity of their code.
- Neither Microchip nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not
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